

<b>Notice of References Cited</b>	Application/Control No. 10/564,742	Applicant(s)/Patent Under Reexamination ENDO ET AL.	
	Examiner JACOB MARKS	Art Unit 1729	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,393,476	07-2008	Shiozaki et al.	252/521.2
*	B	US-2003/0211391	11-2003	Cho et al.	429/218.1
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 03/044881	05-2003	Japan	Shiozaki	
	O	CN 1416189	05-2003	China	Chen	
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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